Statistical	
\overline{p} yields	0.5 - 11% (< 2% for most bins)
Luminosity	1.5 - 2.3%
Correlated systematic	
Luminosity	6.0%
Event and PV selection	0.3%
PV reconstruction	0.4-2.9%
Tracking	1.3-4.1%
Non-prompt background	0.3-0.5%
Target purity	0.1%
PID	3.0 - 6.0%
Uncorrelated systematic	
Tracking	1.0%
IP cut efficiency	1.0%
PV reconstruction	1.6%
PID	0 - 36% (< 5% for most bins)
Simulated sample size	0.4 - 11% (< 2% for most bins)